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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number + -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP 62-257698	11/10/1987	TANAKA, et al.		abstract	
		JP 7-161840	06/23/1995	SASAKI		abstract	
		JP 6-291281	10/18/1994	MANO		abstract	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
NAI		NAIKI, et al. "Center Wordline Cell: A New Symmetric Layout Cell for 64Mb SRAM" International Electron Devices Meeting Technical Digest, Washington, D.C. (December 5-8, 1993) pp. 33.3.1-33.3.4.

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